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(54) **METHOD AND APPARATUS FOR TRAINING CELL DEFECT DETECTION MODEL**

VERFAHREN UND VORRICHTUNG ZUM TRAINIEREN EINES MODELLS FÜR DIE ERKENNUNG
VON ZELLFEHLERN

PROCÉDÉ ET DISPOSITIF D'ENTRAÎNEMENT POUR UN MODÈLE DE DÉTECTION DE DÉFAUTS
D'UNE CELLULE

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